

Dual N-channel MOSFET with schottky diode

ELM14912AA-N

General description

ELM14912AA-N uses advanced trench technology to provide excellent $R_{ds(on)}$ and low gate charge.

Features

Q1	Q2	Schottky diode
• $V_{ds}=30V$	$V_{ds}=30V$	• $V_{ds}(V)=30V$
• $I_d=8.5A$	$I_d=7A$ ($V_{gs}=10V$)	• $I_f=3A$
• $R_{ds(on)} < 17m\Omega$	$< 26m\Omega$ ($V_{gs}=10V$)	• $V_f < 0.5V@1A$
• $R_{ds(on)} < 25m\Omega$	$< 31m\Omega$ ($V_{gs}=4.5V$)	

Maximum absolute ratings

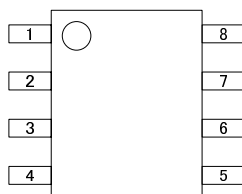
Parameter	Symbol	Max. Q1	Max. Q2	Max.Schottky	Unit	Note
Drain-source voltage	V_{ds}	30	30		V	
Gate-source voltage	V_{gs}	± 20	± 12		V	
Continuous drain current	$T_a=25^\circ C$	8.5	7.0		A	1
	$T_a=70^\circ C$	6.8	6.4			
Pulsed drain current	I_{dm}	40	30		A	2
Avalanche current	I_{av}	17	15		A	2
Repetitive avalanche energy 0.3mH	E_{av}	43	34		mJ	2
Schottky reverse voltage	V_{ka}			30	V	
Continuous forward current	$T_a=25^\circ C$			3.0	A	1
	$T_a=70^\circ C$			2.2		
Pulsed diode forward current	I_{fm}			20	A	2
Power dissipation	$T_a=25^\circ C$	2.00	2.00	2.00	W	1
	$T_a=70^\circ C$	1.28	1.28	1.28		
Junction and storage temperature range	T_j, T_{stg}	-55 to 150	-55 to 150	-55 to 150	$^\circ C$	

Thermal characteristics

Parameter (Q1,Q2)		Symbol	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$t \leq 10s$	$R_{\theta ja}$	48.0	62.5	$^\circ C/W$	1
Maximum junction-to-ambient	Steady-state		74.0	110.0	$^\circ C/W$	
Maximum junction-to-lead	Steady-state	$R_{\theta jl}$	35.0	40.0	$^\circ C/W$	3
Parameter (Schottky)		Symbol	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$t \leq 10s$	$R_{\theta ja}$	47.5	62.5	$^\circ C/W$	1
Maximum junction-to-ambient	Steady-state		71.0	110.0	$^\circ C/W$	
Maximum junction-to-lead	Steady-state	$R_{\theta jl}$	32.0	40.0	$^\circ C/W$	3

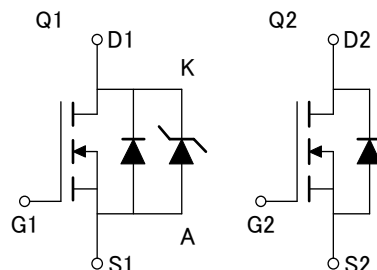
Pin configuration

SOP-8 (TOP VIEW)



Pin No.	Pin name
1	DRAIN2
2	DRAIN2
3	GATE1
4	SOURCE1/ANODE
5	DRAIN1/SOURCE2/CATHODE
6	DRAIN1/SOURCE2/CATHODE
7	DRAIN1/SOURCE2/CATHODE
8	GATE2

Circuit



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■Electrical characteristics (Q1)

Ta=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
STATIC PARAMETERS						
Drain-source breakdown voltage	BV _{dss}	I _d =250 μ A, V _{gs} =0V	30			V
Zero gate voltage drain current (Set by Schottky leakage)	I _{dss}	V _r =30V		0.007	0.050	mA
		V _r =30V, T _j =125°C		3.2	10.0	
		V _r =30V, T _j =150°C		12.0	20.0	
Gate-body leakage current	I _{gss}	V _d =0V, V _{gs} = $\pm$ 20V			100	nA
Gate threshold voltage	V _{gs(th)}	V _d =V _{gs} , I _d =250 μ A	1.0	1.8	3.0	V
On state drain current	I _{d(on)}	V _{gs} =4.5V, V _d =5V	30			A
Static drain-source on-resistance	R _{ds(on)}	V _{gs} =10V		13.8	17.0	m Ω
		I _d =8.5A, T _j =125°C		20.0	24.0	
		V _{gs} =4.5V, I _d =7A		19.7	25.0	m Ω
Forward transconductance	G _{fs}	V _d =5V, I _d =8.5A		23		S
Diode+Schottky forward voltage	V _{sd}	I _s =1A		0.45	0.50	V
Max. body-diode+Schottky continuous current	I _s				3.5	A
DYNAMIC PARAMETERS						
Input capacitance	C _{iss}	V _{gs} =0V, V _d =15V, f=1MHz		971	1165	pF
Output capacitance (FET+Schottky)	C _{oss}			190		pF
Reverse transfer capacitance	C _{rss}			110	154	pF
Gate resistance	R _g	V _{gs} =0V, V _d =0V, f=1MHz	0.35	0.70	0.85	Ω
SWITCHING PARAMETERS						
Total gate charge (10V)	Q _g	V _{gs} =10V, V _d =15V, I _d =8.5A		19.20	23.00	nC
Total gate charge	Q _g			9.36	11.20	nC
Gate-source charge	Q _{gs}			2.60		nC
Gate-drain charge	Q _{gd}			4.20		nC
Turn-on delay time	t _{d(on)}	V _{gs} =10V, V _d =15V R _l =1.8 Ω , R _{gen} =3 Ω		5.2	7.5	ns
Turn-on rise time	t _r			4.4	6.5	ns
Turn-off delay time	t _{d(off)}			17.3	25.0	ns
Turn-off fall time	t _f			3.3	5.0	ns
Body diode+Schottky reverse recovery time	t _{rr}	I _f =8.5A, dI/dt=100A/ μ s		19.3	23.0	ns
Body diode+Schottky reverse recovery charge	Q _{rr}	I _f =8.5A, dI/dt=100A/ μ s		9.4	11.0	nC

NOTE :

1. The value of R θ _{ja} is measured with the device mounted on 1in² FR-4 board of 2oz. Copper, in still air environment with Ta=25°C. The value in any given applications depends on the user's specific board design, The current rating is based on the t $\leq$ 10s themal resistance rating.
2. Repetitive rating, pulse width limited by junction temperature.
3. The R θ _{ja} is the sum of the thermal impedance from junction to lead R θ _{jl} and lead to ambient.
4. The static characteristics in Figures 1 to 6 are obtained using 80 μ s pulses, duty cycle 0.5%max.
5. These tests are performed with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with Ta=25°C. The SOA curve provides a single pulse rating.
6. The Schottky appears in parallel with the MOSFET body diode, even though it is a separate chip. Therefore, we provide the net forward drop, capacitance and recovery characteristics of the MOSFET and Schottky. However, the thermal resistance is specified for each chip separately.

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Typical electrical and thermal characteristics (Q1)

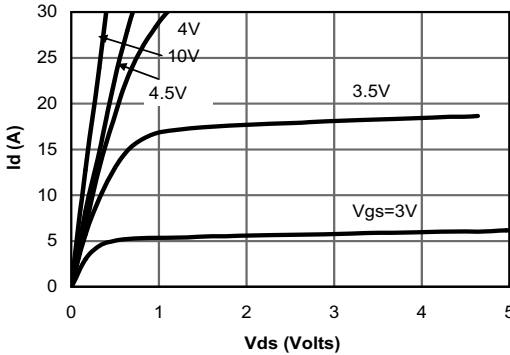


Fig 1: On-Region Characteristics

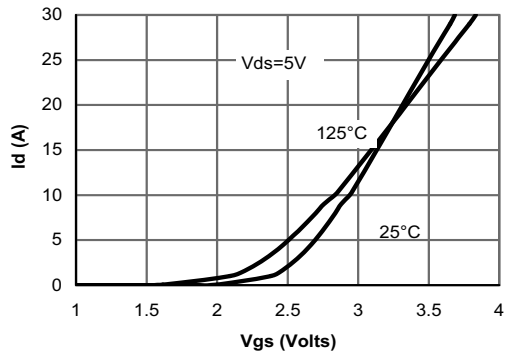


Figure 2: Transfer Characteristics

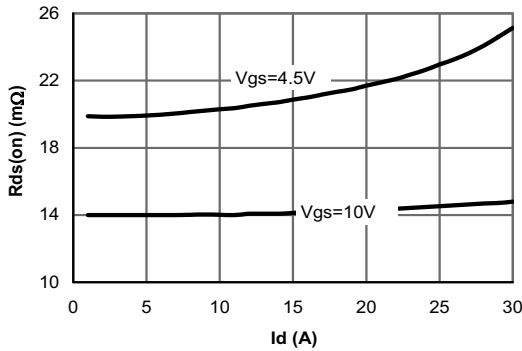


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

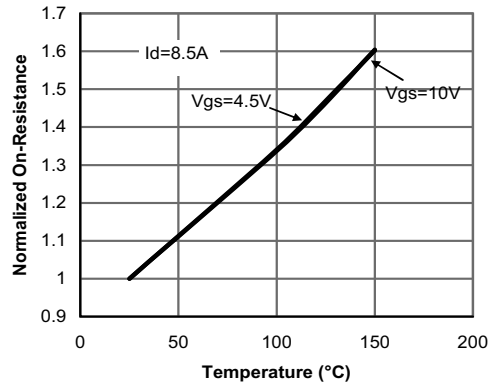


Figure 4: On resistance vs. Junction Temperature

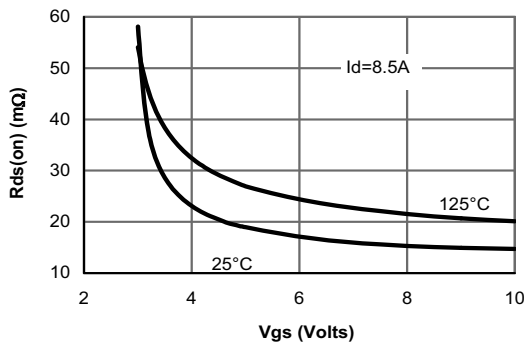


Figure 5: On resistance vs. Gate-Source Voltage

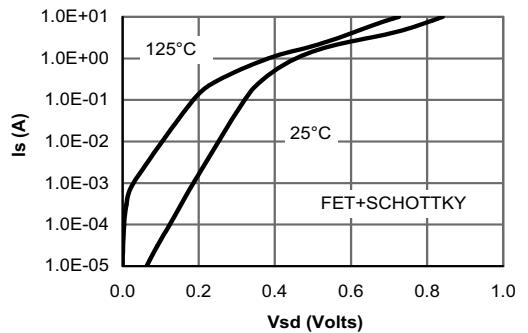


Figure 6: Body-Diode Characteristics (Note 6)

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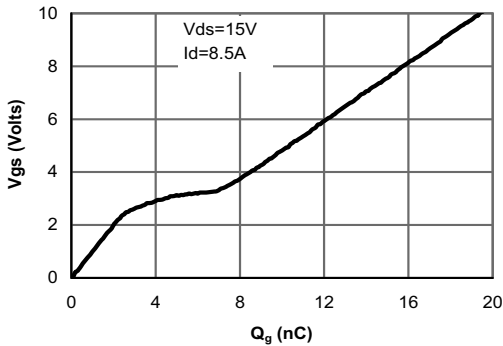


Figure 7: Gate-Charge Characteristics

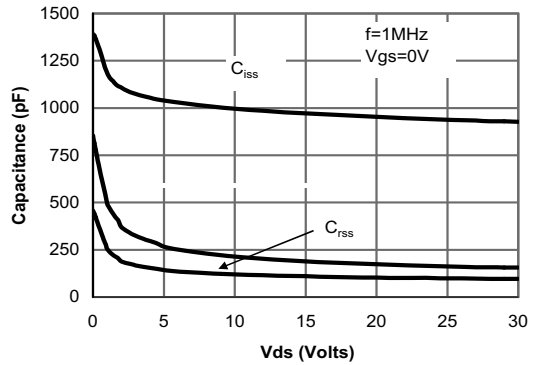


Figure 8: Capacitance Characteristics

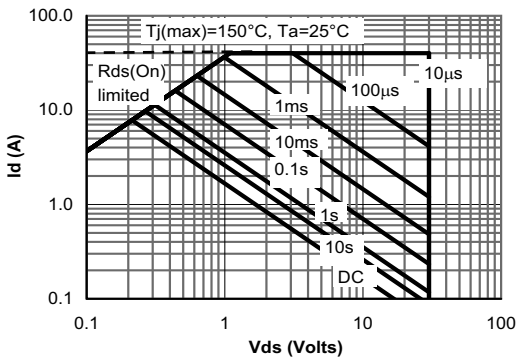


Figure 9: Maximum Forward Biased Safe Operating Area (Note 5)

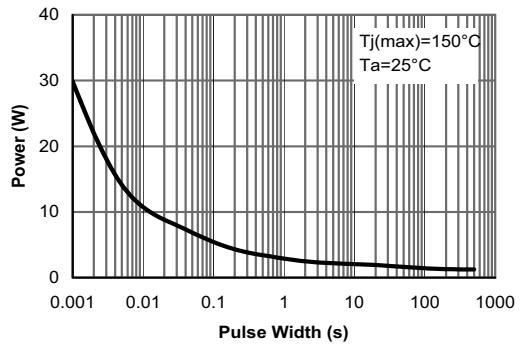


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note 5)

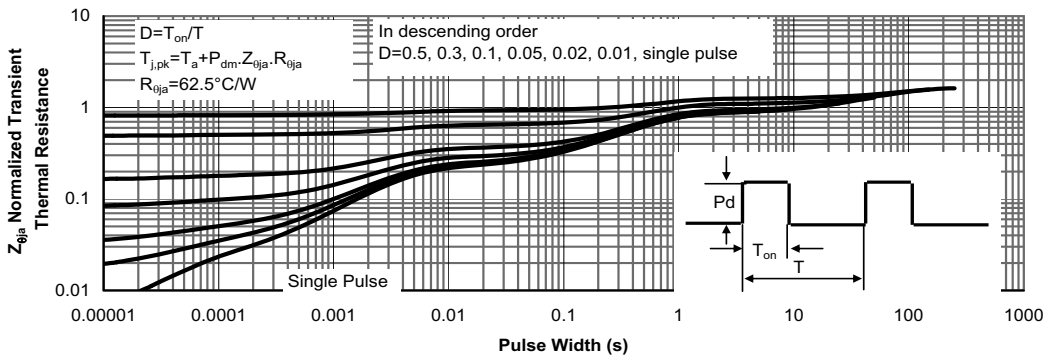


Figure 11: Normalized Maximum Transient Thermal Impedance

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■ Electrical characteristics (Q2)

T_a=25°C

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
STATIC PARAMETERS						
Drain-source breakdown voltage	BV _{dss}	I _d =250 μA, V _{gs} =0V	30			V
Zero gate voltage drain current	I _{dss}	V _d =30V V _{gs} =0V			1	μA
		T _j =55°C			5	
Gate-body leakage current	I _{gss}	V _d =0V, V _{gs} =±12V			100	nA
Gate threshold voltage	V _{gs(th)}	V _d =V _{gs} , I _d =250 μA	1.0	1.5	2.0	V
On state drain current	I _{d(on)}	V _{gs} =4.5V, V _d =5V	25			A
Static drain-source on-resistance	R _{ds(on)}	V _{gs} =10V I _d =7A		20.0	26.0	mΩ
		T _j =125°C		31.6	38.0	
		V _{gs} =4.5V, I _d =6A		24.3	31.0	mΩ
Forward transconductance	G _{fs}	V _d =5V, I _d =7A		22		S
Diode forward voltage	V _{sd}	I _s =1A		0.78	1.00	V
Max. body-diode continuous current	I _s				3	A
DYNAMIC PARAMETERS						
Input capacitance	C _{iss}	V _{gs} =0V, V _d =15V, f=1MHz		590	710	pF
Output capacitance	C _{oss}			162		pF
Reverse transfer capacitance	C _{rss}			40	56	pF
Gate resistance	R _g	V _{gs} =0V, V _d =0V, f=1MHz	0.20	0.45	0.60	Ω
SWITCHING PARAMETERS						
Total gate charge	Q _g	V _{gs} =4.5V, V _d =15V, I _d =7A		6.04	7.30	nC
Gate-source charge	Q _{gs}			1.46		nC
Gate-drain charge	Q _{gd}			2.56		nC
Turn-on delay time	t _{d(on)}	V _{gs} =10V, V _d =15V R _L =2.2 Ω, R _{gen} =3 Ω		3.7	5.5	ns
Turn-on rise time	t _r			3.5	5.5	ns
Turn-off delay time	t _{d(off)}			14.9	22.0	ns
Turn-off fall time	t _f			2.5	4.0	ns
Body diode reverse recovery time	t _{rr}	I _f =7A, dI/dt=100A/μs		21.2	26.0	ns
Body diode reverse recovery charge	Q _{rr}	I _f =7A, dI/dt=100A/μs		14.2	21.0	nC

NOTE :

1. The value of R_{θja} is measured with the device mounted on 1in² FR-4 board of 2oz. Copper, in still air environment with T_a=25°C. The value in any given applications depends on the user's specific board design, The current rating is based on the t ≤ 10s thermal resistance rating.
2. Repetitive rating, pulse width limited by junction temperature.
3. The R_{θja} is the sum of the thermal impedance from junction to lead R_{θjl} and lead to ambient.
4. The static characteristics in Figures 1 to 6 are obtained using 80μs pulses, duty cycle 0.5%max.
5. These tests are performed with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_a=25°C. The SOA curve provides a single pulse rating.

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Typical electrical and thermal characteristics (Q2)

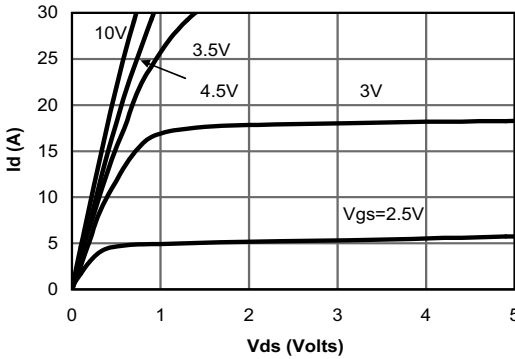


Fig 1: On-Region Characteristics

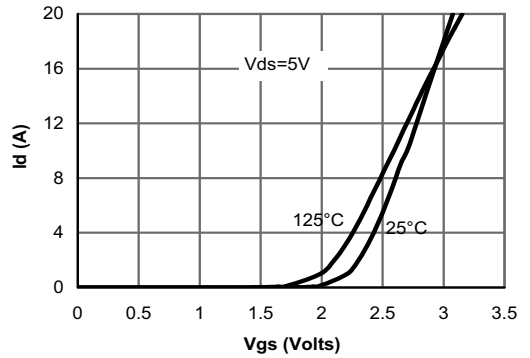


Figure 2: Transfer Characteristics

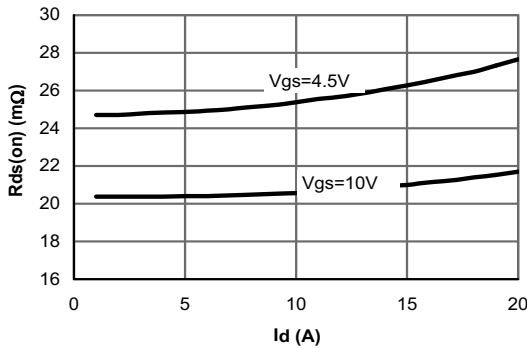


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

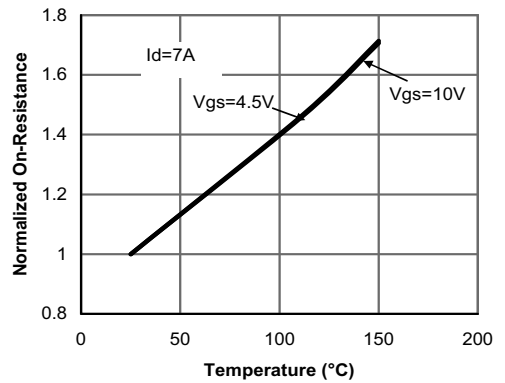


Figure 4: On resistance vs. Junction Temperature

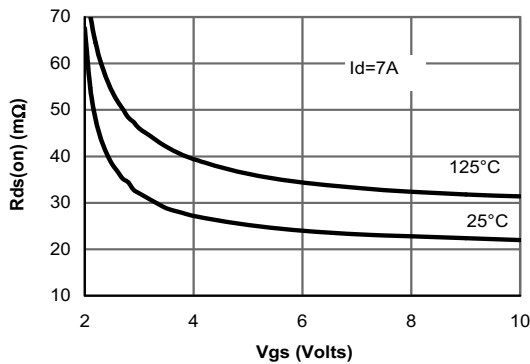


Figure 5: On resistance vs. Gate-Source Voltage

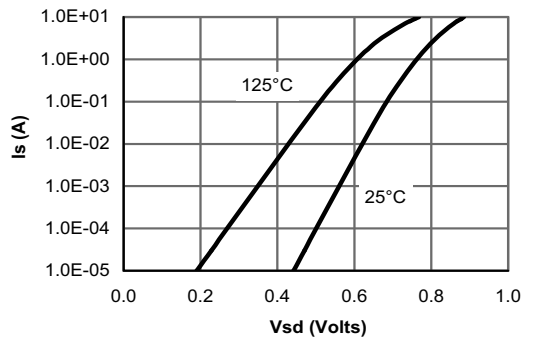


Figure 6: Body-Diode Characteristics

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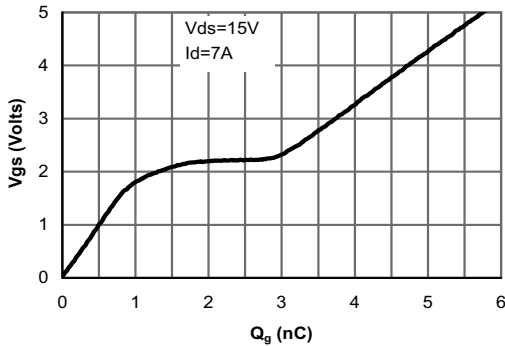


Figure 7: Gate-Charge Characteristics

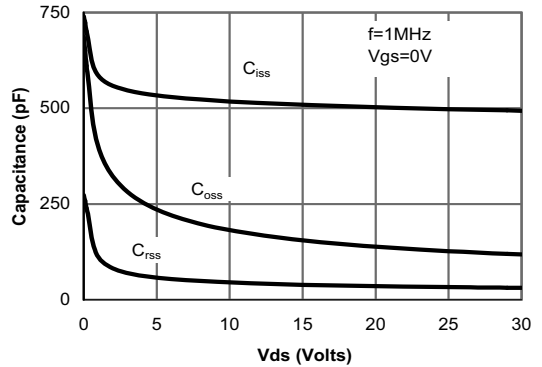


Figure 8: Capacitance Characteristics

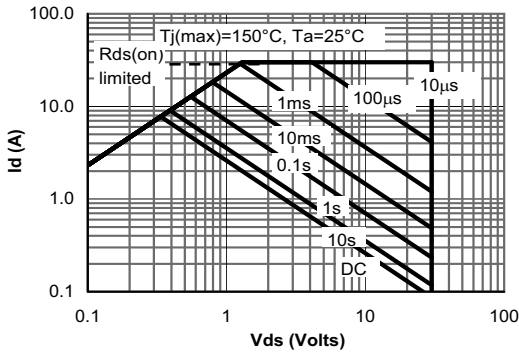


Figure 9: Maximum Forward Biased Safe Operating Area (Note 5)

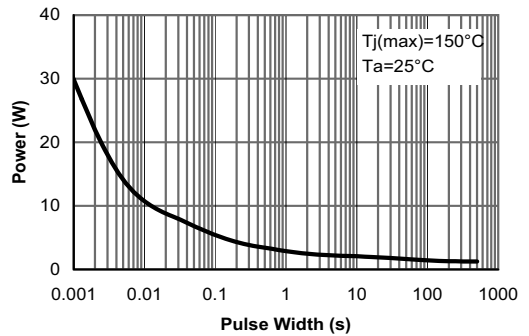


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note 5)

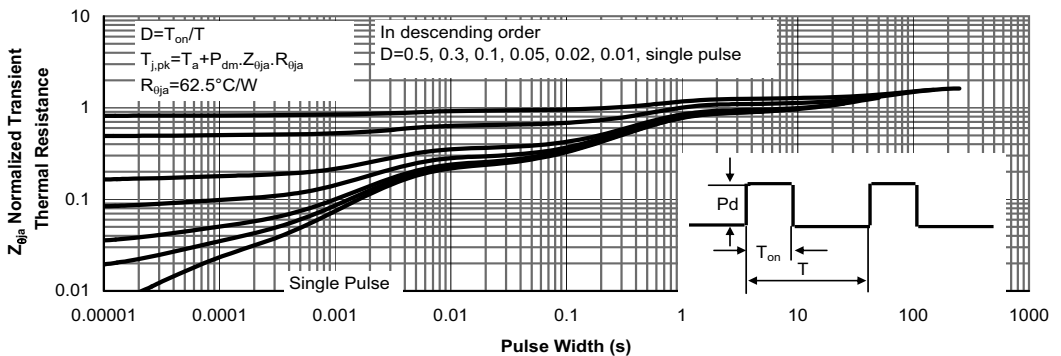


Figure 11: Normalized Maximum Transient Thermal Impedance